

Notice of References Cited	Application/Control No. 10/762,985		Applicant(s)/Patent Under Reexamination KONING ET AL.	
	Examiner SARGON NANO		Art Unit 2457	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,978,844	11-1999	Tsuchiya et al.	709/221
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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